# MOSFET - N-Channel, UniFET™, FRFET® 500 V, 45 A, 120 mΩ

# FDH45N50F

#### **Description**

UniFET MOSFET is ON Semiconductor's high voltage MOSFET family based on planar stripe and DMOS technology. This MOSFET is tailored to reduce on–state resistance, and to provide better switching performance and higher avalanche energy strength. The body diode's reverse recovery performance of UniFET FRFET MOSFET has been enhanced by lifetime control. Its t<sub>rr</sub> is less than 100 nsec and the reverse dv/dt immunity is 15 V/ns while normal planar MOSFETs have over 200 nsec and 4.5 V/nsec respectively. Therefore, it can remove additional component and improve system reliability in certain applications in which the performance of MOSFET's body diode is significant. This device family is suitable for switching power converter applications such as power factor correction (PFC), flat panel display (FPD) TV power, ATX and electronic lamp ballasts.

#### **Features**

- $R_{DS(on)} = 105 \text{ m}\Omega \text{ (Typ.)} @ V_{GS} = 10 \text{ V}, I_D = 22.5 \text{ A}$
- Low Gate Charge (Typ. 105 nC)
- Low C<sub>rss</sub> (Typ. 62 pF)
- 100% Avalanche Tested
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

## **Applications**

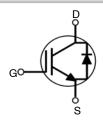
- Lighting
- Uninterruptible Power Supply
- AC-DC Power Supply



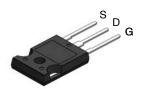
## ON Semiconductor®

#### www.onsemi.com

V <sub>DS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
500 V	120 mΩ @ 10 V	45 A

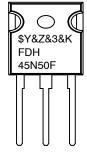


#### **N-CHANNEL MOSFET**



TO-247-3LD CASE 340CK

#### **MARKING DIAGRAM**



\$Y

= ON Semiconductor Logo

&Z &3 Assembly Plant CodeNumeric Date Code

&K

= Lot Code

FDH45N50F

= Specific Device Code

#### **ORDERING INFORMATION**

See detailed ordering and shipping information on page 2 of this data sheet.

## ABSOLUTE MAXIMUM RATINGS ( $T_C = 25$ °C unless otherwise noted)

Symbol	Parameter		FDH45N50F-F133	Unit
V <sub>DSS</sub>	Drain to Source Voltage		500	V
Ι <sub>D</sub>	Drain Current –	-Continuous ( $T_C = 25$ °C) -Continuous ( $T_C = 100$ °C)	45 28.4	A A
I <sub>DM</sub>	Drain Current	-Pulsed (Note 1)	180	Α
$V_{GSS}$	Gate-Source Voltage		±30	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)		1868	mJ
I <sub>AR</sub>	Avalanche Current (Note 1)		45	Α
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1)		62.5	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		50	V/ns
P <sub>D</sub>	Power Dissipation	(T <sub>C</sub> = 25°C) -Derate Above 25°C	625 5	W W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range	)	−55 to + 150	°C
T <sub>L</sub>	Maximum Lead Temperature for Soldering,	1/8" from Case for 5 Second	300	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Repetitive Rating: Pulse width limited by maximum junction temperature.

2. L = 1.46 mH,  $I_{AS}$  = 48 A,  $V_{DD}$  = 50 V,  $R_{G}$  = 25  $\Omega$ , Starting  $T_{J}$  = 25 °C.

3.  $I_{SD} \le 45$  A, di/dt  $\le 200$  A/ $\mu$ s,  $V_{DD} \le BV_{DSS}$ , Starting  $T_{J}$  = 25 °C.

## PACKAGE MARKING AND ORDERING INFORMATION

	Device Marking	Device	Package	Package Method	Reel Size	Tape Width	Quantity
Ī	FDH45N50F-F133	FDH45N50F	TO-247-3	Tube	-	-	30 Units

## THERMAL CHARACTERISTICS

Symbol	Parameter	FDH45N50F-F133	Unit
$R_{ heta JC}$	Thermal Resistance, Junction to Case, Max.	0.2	°C/W
$R_{ heta JA}$	Thermal Resistance, Junction to Ambient, Max.	40	

# **ELECTRICAL CHARACTERISTICS** ( $T_C = 25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Unit
OFF CHARA	ACTERISTICS	•	•	-		
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	500	_	-	V
$\Delta BV_{DSS} / \Delta T_{J}$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, Referenced to 25°C	-	0.5	-	V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 500 V, V <sub>GS</sub> = 0 V	-	_	25	μΑ
		V <sub>DS</sub> = 400 V, T <sub>C</sub> = 125°C	-	_	250	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V	-	_	100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$	-	_	-100	nA
ON CHARA	CTERISTICS					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	3	-	5	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 22.5 A	-	0.105	0.12	Ω
9FS	Forward Transconductance	V <sub>DS</sub> = 40 V, I <sub>D</sub> = 22.5 A	-	49	-	S
DYNAMIC C	HARACTERISTICS		•			
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1 MHz	-	5100	6630	pF
C <sub>oss</sub>	Output Capacitance	1	-	790	1030	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1	-	62	-	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 400 V, V <sub>GS</sub> = 0 V, f = 1 MHz	-	161	-	pF
C <sub>oss</sub> eff.	Effective Output Capacitance	V <sub>DS</sub> = 0 V to 400 V, V <sub>GS</sub> = 0 V	-	342	-	pF
SWITCHING	CHARACTERISTICS		_			
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 250 V, I <sub>D</sub> = 48 A,	-	140	290	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, R_G = 25 \Omega$ (Note 4)	-	500	1010	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	(1010 1)	-	215	440	ns
t <sub>f</sub>	Turn-Off Fall Time	1	-	245	500	ns
Qg	Total Gate Charge	V <sub>DS</sub> = 400 V, I <sub>D</sub> = 48 A, V <sub>GS</sub> = 10 V	-	105	137	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V (Note 4)	-	33	-	nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note 1)	-	45	-	nC
	RCE DIODE CHARACTERISTICS AND N	IAXIMUM RATINGS	-			
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current		_	_	45	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current		-	_	180	Α
V <sub>SD</sub>	Source to Drain Diode Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 45 A	_	_	1.4	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 45 A,	-	188	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	dl <sub>F</sub> /dt = 100 A/μs	_	0.64	_	μC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Essentially Independent of Operating Temperature Typical Characteristics.

#### **TYPICAL CHARACTERISTICS**

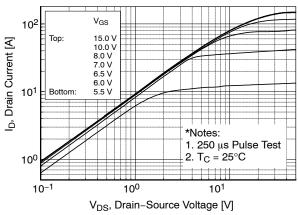


Figure 1. On-Region Characteristics

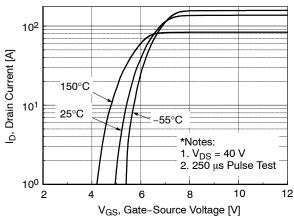


Figure 2. Transfer Characteristics

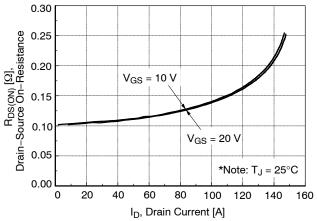


Figure 3. On–Resistance Variation vs. Drain Current and Gate voltage

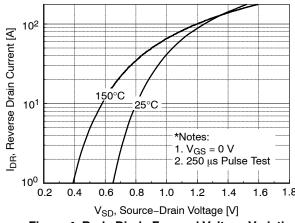


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

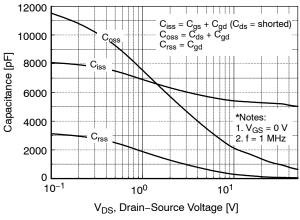


Figure 5. Capacitance Characteristics

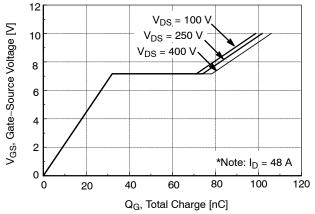


Figure 6. Gate Charge Characteristics

#### **TYPICAL CHARACTERISTICS**

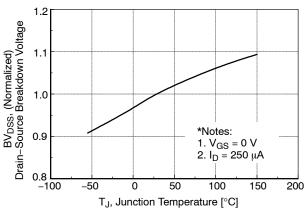


Figure 7. Breakdown Voltage Variation vs. Temperature

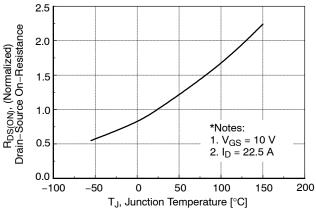


Figure 8. On-Resistance Variation vs. Temperature

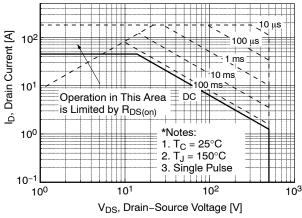


Figure 9. Maximum Safe Operating Area

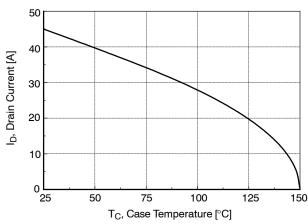


Figure 10. Maximum Drain Current vs. Case Temperature

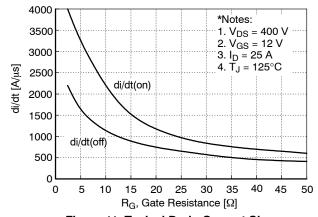


Figure 11. Typical Drain Current Slope vs. Gate Resistance

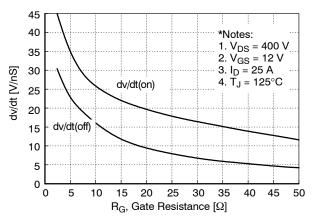


Figure 12. Typical Drain-Source Voltage Slope vs. Gate Resistance

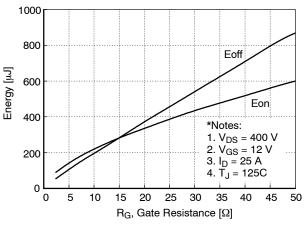


Figure 13. Typical Switching Losses vs. Gate Resistance

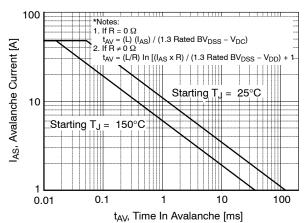


Figure 14. Unclamped Inductive Switching Capability

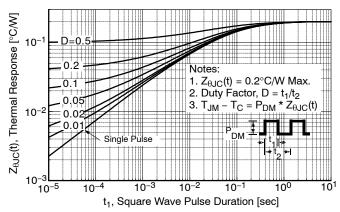


Figure 15. Transient Thermal Resistance Curve

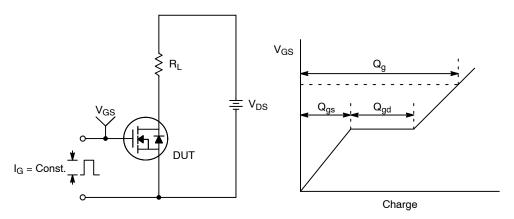


Figure 16. Gate Charge Test Circuit & Waveform

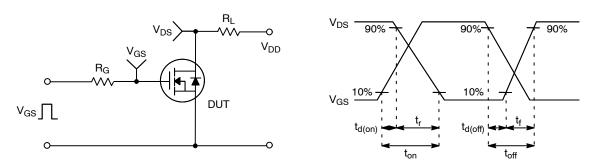


Figure 17. Resistive Switching Test Circuit & Waveforms

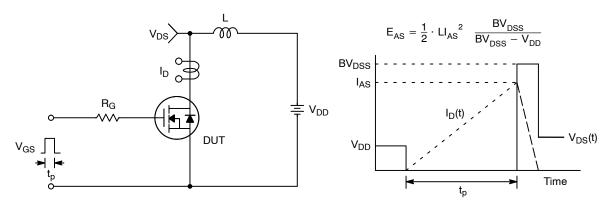


Figure 18. Unclamped Inductive Switching Test Circuit & Waveforms

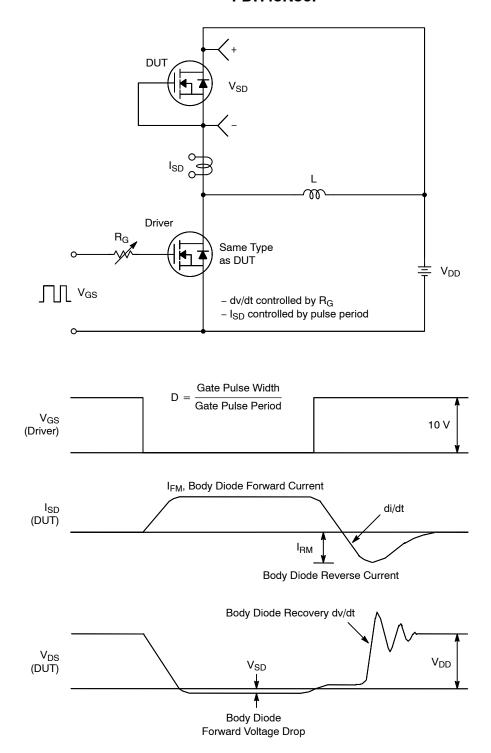


Figure 19. Peak Diode Recovery dv/dt Test Circuit & Waveforms

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#### TO-247-3LD SHORT LEAD

CASE 340CK ISSUE A





- A. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
- B. ALL DIMENSIONS ARE IN MILLIMETERS.
- C. DRAWING CONFORMS TO ASME Y14.5 2009.
- D. DIMENSION A1 TO BE MEASURED IN THE REGION DEFINED BY L1.
- E. LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY L1.

# GENERIC MARKING DIAGRAM\*



XXXX = Specific Device Code

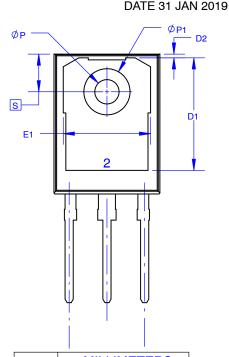
A = Assembly Location

Y = Year

WW = Work Week

ZZ = Assembly Lot Code

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.



DIM	MILLIMETERS				
DIIVI	MIN	NOM	MAX		
Α	4.58	4.70	4.82		
<b>A</b> 1	2.20	2.40	2.60		
A2	1.40	1.50	1.60		
b	1.17	1.26	1.35		
b2	1.53	1.65	1.77		
b4	2.42	2.54	2.66		
С	0.51	0.61	0.71		
D	20.32	20.57	20.82		
D1	13.08	~	~		
D2	0.51	0.93	1.35		
E	15.37	15.62	15.87		
E1	12.81	?	~		
E2	4.96	5.08	5.20		
е	~	5.56	~		
L	15.75	16.00	16.25		
L1	3.69	3.81	3.93		
ØΡ	3.51	3.58	3.65		
ØP1	6.60	6.80	7.00		
Q	5.34	5.46	5.58		
S	5.34	5.46	5.58		

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DESCRIPTION:	TO-247-3LD SHORT LEAD		PAGE 1 OF 1

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